

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1267	Oct-95	9544 A1	HYUNDAI	DL508411AAK	1.2μ OX/NI	16 SOIC

STRESS/JOB NO.

READPOINT

(Sample Size/No. of Fails)

Preconditioning (P/C):
85°C/85% RH, 168 hours
HTC Vapor Phase, 3 Passes
P-16441

Electrical	Cum %
304/0	0.0%

Sonoscan
P-16440

Post Vapor Phase
2/0

Infant / High Voltage Life
125°C, -4.0 & +6.0 V
P-16685, P-16695

48 Hr	336 Hr	1K Hr	*Failure Rate
304/0	116/0	116/0	55 Fits

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-16696

300 ~	1K ~	Cum %
77/0	77/0	0.0%

Biased Moisture (HAST)
120°C/85% RH, 5.5 V.
P-16697

100 Hr	200 Hr	Cum %
66/0	66/0	0.0%

Autoclave
121°C/100% RH, 2 Atmos
P-16698

168 Hr	Cum %
45/1	2.2%
F1	

Failure Mode

F1: Output Current